

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/642,896	TAKANO ET AL.	
Examiner	Art Unit	
Frank Duong	2616	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST SEARCH (see printout)	5/16/2007	FD	
INVENTORSHIP SEARCH (see printout)	5/16/2007	FD	
IEEE/INTERNET SEARCH	5/16/2007	FD	